

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
1380-01SERIAL NO.  
10/019,819

## LIST OF PRIOR ART CITED BY APPLICANT

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Christopher R  th et al.FILING DATE  
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## U.S. PATENT DOCUMENTS

EXAMINER INITIAL*		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
A-A	AL	DE 43 17 746 A1 (Corr. US Patent No. 5,822,466)	12/1/84	Germany	382	260	X	
↓	AM	DE 196 33 693 C1 (Corr. US Patent No. 5,923,780)	11/20/97	Germany	382	195	X	
	AN							
	AO							
	AP							

## OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

A-A	AR	M. Tuceryan et al., Handbook of Pattern Recognition and Computer Vision, "Texture Analysis", World Scientific, Publishing, 1993, pp 235-276
↓	AS	R. C. Dubes, Handbook of Pattern Recognition and Computer Vision, "Cluster Analysis and Related Issues", World Scientific Publishing, 1993, pp 3-32
↓	AT	R. M. Haralick, Proceedings of the IEEE, "Statistical and Structural Approaches to Texture", Vol. 67, No. 5, May 1979, pp 786-804

EXAMINER

AMIR ALAUI

DATE CONSIDERED

11-03-04

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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F.A.	AR	F. W. Campbell et al., J. Physiol, "Application of Fourier Analysis to the Visibility of Gratings", Vol 197, 1968, pp 551-566
	AS	R. De Valois et al., Vision Res., "Spatial Frequency Selectivity of Cells in Macaque Visual Cortex", Vol 22, 1982, pp 545-559
✓	AT	A.K. Jain et al., Pattern Recognition, "Unsupervised Texture Segmentation Using Gabor Filters", Vol 24, No. 12, 1991, pp 1167-1186

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A.A.	AR	B.D. Ripley, "Pattern Recognition and Neural Networks", Cambridge University Press 1996
	AS	A.M. Bensaid et al., Pattern Recognition, "Partially Supervised Clustering for Image Segmentation" Vol. 29, 1996, pp 859-871
↓	AT	L. Abele, "Bildsegmentation mittels struktureller Texturanalyse", Springer-Verlag, 1979, pages 269-279 (with abstract)

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A.F.	AR	O. Pichler et al., "Rotations-und skaleninvariante Textursegmentierung mit Mehrkanalfilterung", 1997, pp 79-86 (with abstract)
	AS	T. Randen, J.H. Husoy, IEEE Transactions on Pattern Analysis and Machine Intelligence, "Filtering for Texture Classification: A Comparative Study", Vol. 21, No. 4, pp. 291-310
	AT	Bela Julesz, Review of Modern Physics, "Early Vision and Focal Attention", Vol. 63, 1991, pp 735-772

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A.A. ↓	AR	Y. Hu et al., IEE Proc.-Vis. Image Signal Process., "Textured Image Segmentation by Context Enhanced Clustering", Vol. 141 No. 6, 12/94, pp 413-421
	AS	D.H. Ballard et al., Computer Vision, "Texture as a Pattern Recognition Problem", pp 181-184
	AT	I. Pitas et al., IEE, "Texture Analysis and Segmentation of Seismic Images", Conf. 14, 1989, pp 1437-1440

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